

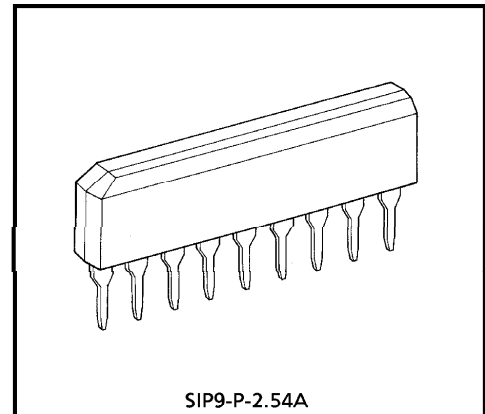
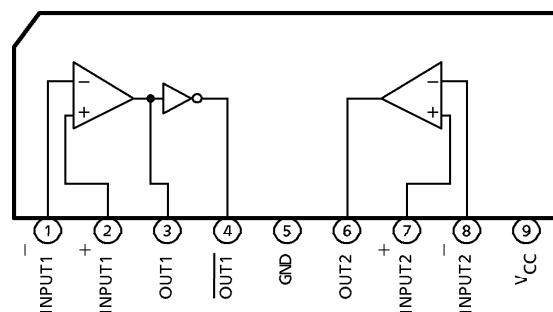
TOSHIBA BIPOLAR LINEAR INTEGRATED CIRCUIT SILICON MONOLITHIC

TA7522S**DUAL VOLTAGE COMPARATOR**

The TA7522S is an easy-to-use small 9-pin single in-line package IC incorporating two voltage comparator circuits. Since one channel has an inverted-output buffer, a CR oscillator can be easily built up. In addition, the IC has so wide an operating temperature range that it can be used in wide application fields.

FEATURES

- Two-circuit package
- High gain
- Single 3V power supply for operation
- Inverted-output also available
- A 0V input causes action in the IC with a single power supply.
- Wide common-mode input range
- No latch-up
- Operating temperature range : from -40 to 85°C
- Open-collector output

SIP9-P-2.54A
Weight : 0.92g (Typ.)**BLOCK DIAGRAM AND PIN LAYOUT**

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PIN DESCRIPTION

PIN No.	SYMBOL	DESCRIPTION
1	INPUT1 ⁻	Inverted-input pin
2	INPUT1 ⁺	Non-inverted-input pin
3	OUT1	Output pin corresponding to INPUT1
4	$\overline{\text{OUT1}}$	Output pin for inversion of OUT1
5	GND	Grounded
6	OUT2	Output pin corresponding to INPUT2
7	INPUT2 ⁺	Non-inverted-input pin
8	INPUT2 ⁻	Inverted-input pin
9	V _{CC}	Power supply pin

MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Supply Voltage	V _{CC}	- 0.3 to + 18	V
Supply Voltage Surge	V _{CC SURGE}	+ 30 (within 1 second)	V
Power Dissipation	P _D	500	mW
Differential Input Voltage	DV _{IN}	± 18	V
Input Voltage	V _{IN}	- 0.3 to + 18	V
Output Current	I _{SINK}	30	mA
Operating Temperature	T _{opr}	- 40 to + 85	°C
Storage Temperature	T _{stg}	- 55 to + 150	°C

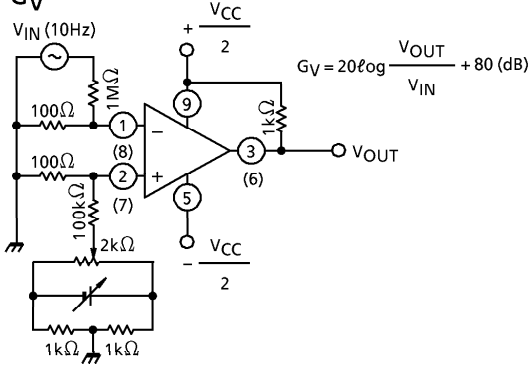
ELECTRICAL CHARACTERISTICS (Ta = -40 to +85°C)

CHARACTERISTIC	SYMBOL	TEST CIR-CUIT	TEST CONDITION	MIN.	(Note) TYP.	MAX.	UNIT
Voltage Gain	G _V	1	V _{CC} = 6V, R _L = 1kΩ f = 10Hz, test circuit 1	60	95	—	dB
Input Offset Voltage	V _{IO}	2	V _{CC} = 6V, R _L = 1kΩ CMV _{IN} = 3V, test circuit 2	—	2	10	mV
Input Bias Current	I _I	3	V _{CC} = 6V, CMV _{IN} = 3V test circuit 3	—	-0.2	-2	μA
Input Offset Current	I _{IO}	3	Same as above	—	0.02	0.3	μA
Common-mode Input Voltage	CMV _{IL}	4	V _{CC} = 6.5V, R _L = 1kΩ V _{IO} = 20mV, test circuit 4	—	-0.5	0	V
	CMV _{IH}		Same as above	5.0	5.3	—	V
Zero Output Voltage	V _{OL}	OUT1 OUT2	V _{CC} = 5.5V, V _{IN} = 0.1V I _{OL} = 10mA, test circuit 5	—	0.18	0.4	V
		$\overline{\text{OUT1}}$	V _{CC} = 5.5V, V _{IN} = 0.1V, I _{OL} = 15mA, V _{OL} (out1) ≥ 2V, test circuit 5	—	0.25	0.4	V
Output Leakage Current	I _{LEAK}	OUT1 OUT1 OUT2	V _{CC} = 6V, V _{OUT} = 30V test circuit 6	—	—	10	μA
		OUT1	V _{CC} = 6V, V _{OUT} = 0.4V test circuit 6	—	-1.5	-10	μA
Current Consumption	I _{CC}	7	V _{CC} = 6.5V, R _L = ∞ test circuit 7	—	3	7	mA

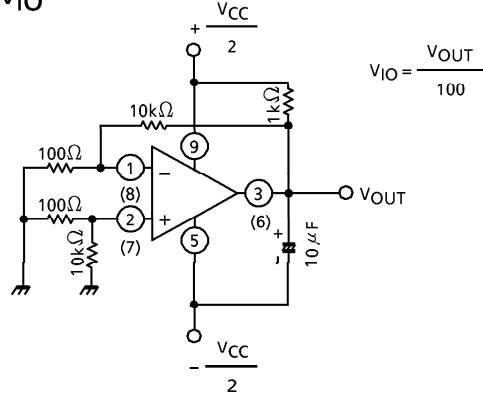
Note : An ambient temperature of 25°C is assumed for the typical values.

TEST CIRCUIT

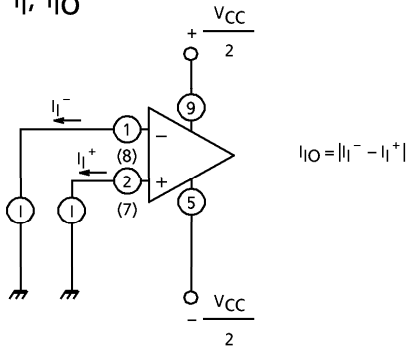
1. G_V



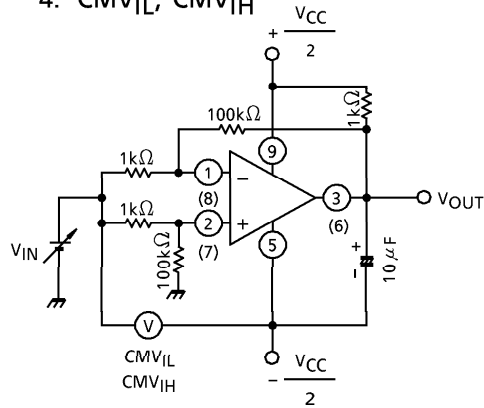
2. V_{IO}



3. I_I, I_{IO}



4. CMV_{IL}, CMV_{IH}

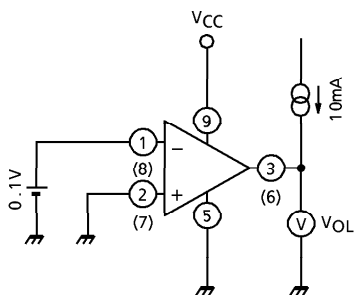


CMV_{IL} : Input voltage relative to pin 5 as it is obtained when V_{IN} is decreased until output V_{OUT} becomes $\pm 2V$.

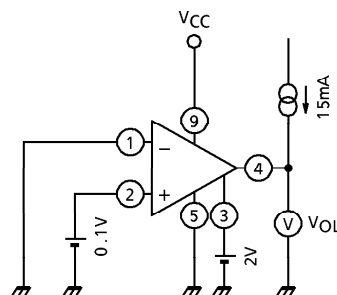
CMV_{IH} : Input voltage relative to pin 5 as it is obtained when V_{IN} is increased until output V_{OUT} becomes $\pm 2V$.

5. V_{OL}

5.1 OUT1, OUT2

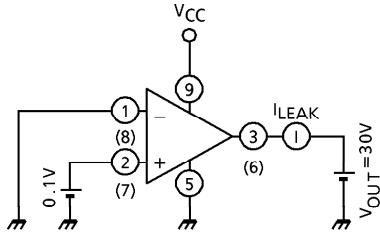


5.2 $\overline{OUT1}$

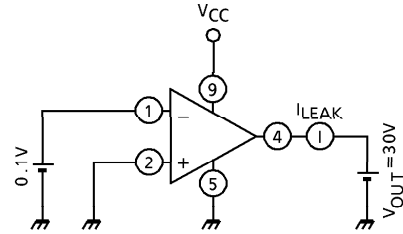


6. I_{LEAK}

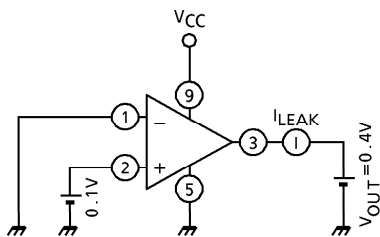
6.1 OUT1, OUT2



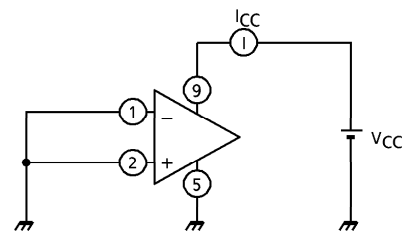
6.2 $\overline{OUT1}$



6.3 OUT1

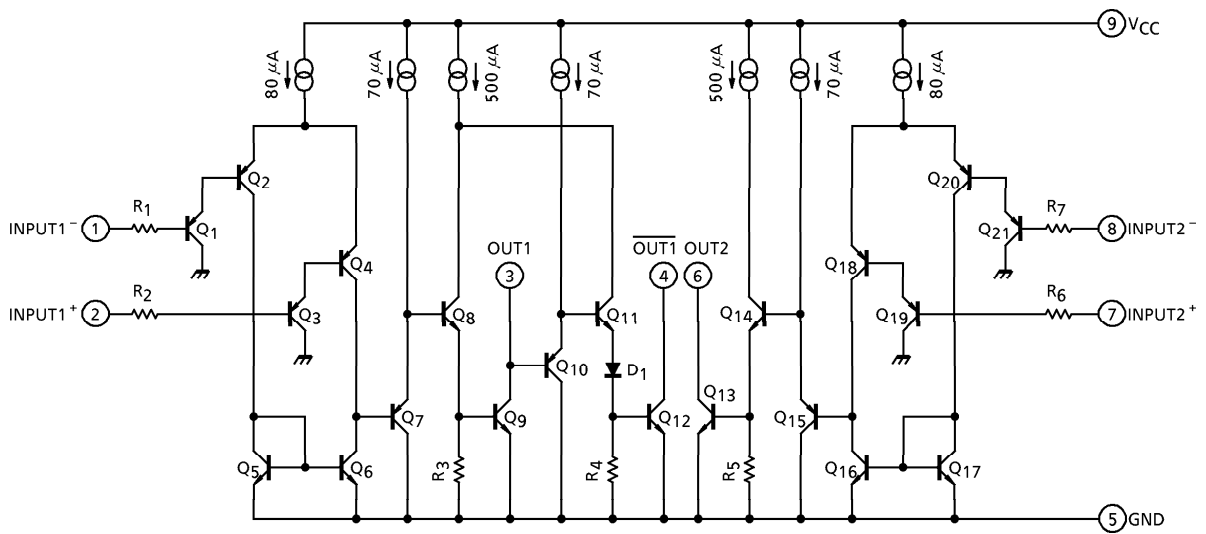


7. I_{CC}



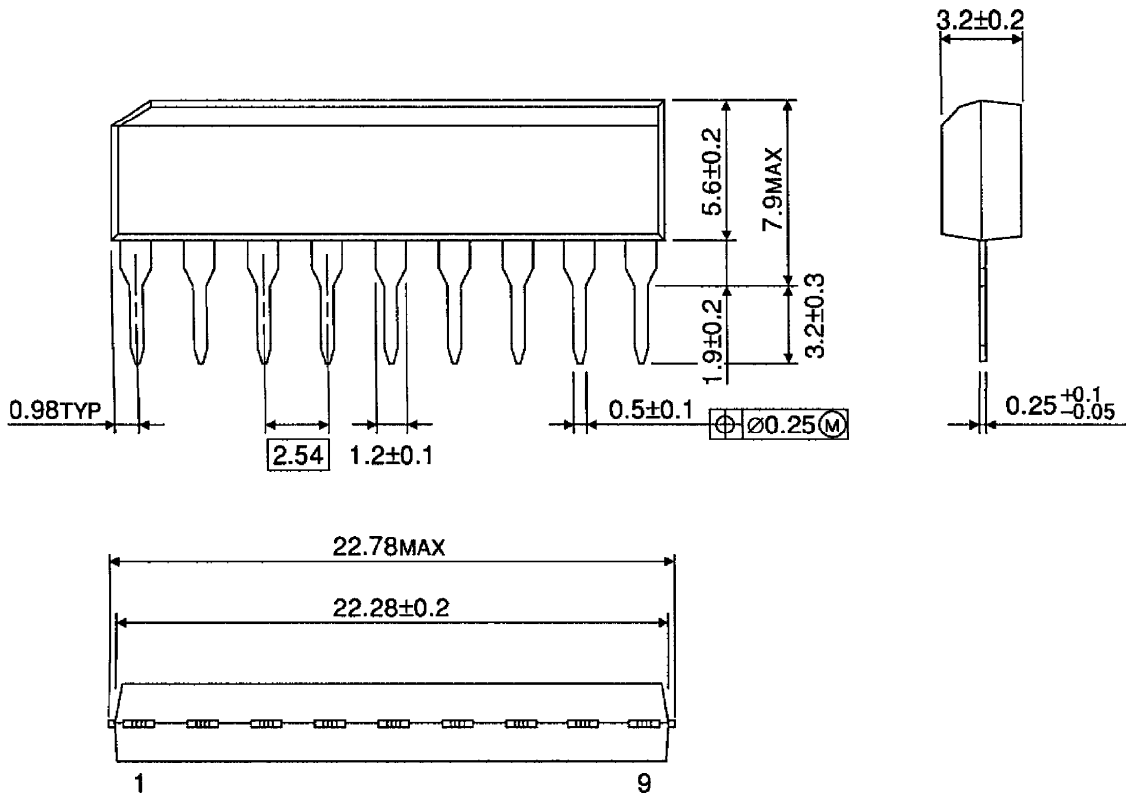
All inputs are grounded.

EQUIVALENT CIRCUIT



OUTLINE DRAWING
SIP9-P-2.54A

Unit : mm



Weight : 0.92g (Typ.)